

Wave optics-based surface encoder

JPPN 2005-321241, JPPN 2006-010645

Background

Multi-degree-of-freedom (MDOF) measurement system

Surface encoder (2D slope sensor + 2D angle grid)

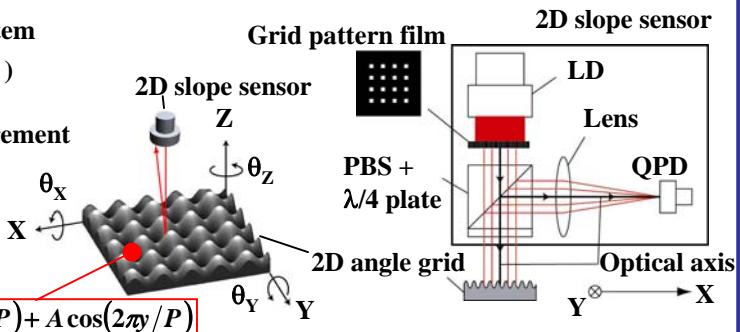
Geometric optics-based design

Advantages : Simple construction, MDOF measurement

Motivation: Wave optics-based design for improving the accuracy and resolution of encoder

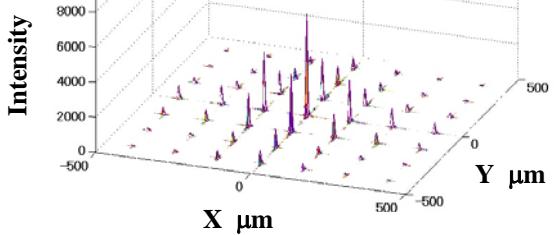
Wave optical analysis

$$h(x, y) = A \cos(2\pi x/P) + A \cos(2\pi y/P)$$

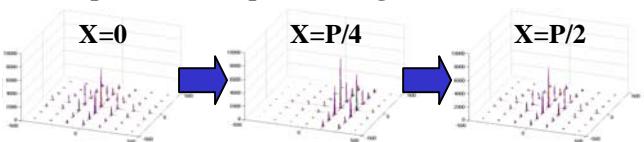


Wave Optical Analysis

Intensity distribution of the spot on the QPD
→ Peaks within a certain period



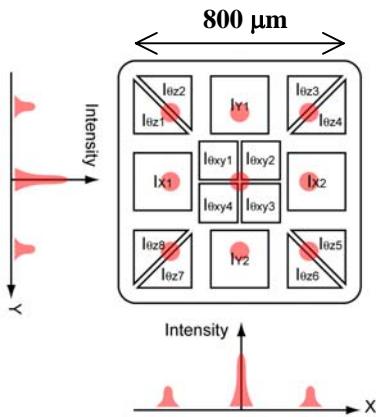
- ① X (Y) directional displacement
→ Amplitude of the peaks change in the X (Y) direction



- ② θ_X (θ_Y) tilt motion
→ Spot movement in the Y (X) direction according to the autocollimation method
- ③ θ_Z rotation motion
→ Spot rotation around the central peak with the same θ_Z angle

5 DOF Measurement Using a Multi-cell Photo Diode

Detecting the spot behaviors with a multi-cell photo diode instead of the QPD, 5 DOF motions are detected



$$S_x = (I_{x2} - I_{x1}) / (I_{x2} + I_{x1}) \times 100\%$$

$$S_y = (I_{y2} - I_{y1}) / (I_{y2} + I_{y1}) \times 100\%$$

$$S_{\theta x} = (I_{\theta x2} + I_{\theta x3} - I_{\theta x1} - I_{\theta x4}) / (I_{\theta x1} + I_{\theta x2} + I_{\theta x3} + I_{\theta x4}) \times 100\%$$

$$S_{\theta y} = (I_{\theta y3} + I_{\theta y4} - I_{\theta y1} - I_{\theta y2}) / (I_{\theta y1} + I_{\theta y2} + I_{\theta y3} + I_{\theta y4}) \times 100\%$$

$$S_{\theta z} = (I_{\theta z2} + I_{\theta z3} + I_{\theta z4} + I_{\theta z8}) - (I_{\theta z1} + I_{\theta z3} + I_{\theta z5} + I_{\theta z7}) / (I_{\theta z1} + I_{\theta z2} + I_{\theta z3} + I_{\theta z4} + I_{\theta z5} + I_{\theta z6} + I_{\theta z7} + I_{\theta z8}) \times 100\%$$

< Simulation results of 5 DOF motion detection >

